

FORM PTO-1449	Atty. Docket No.: 03-2477/L13.12-0258	Appl. No.: 10/817,419
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor:	
	Judy M. Gehman et al.	
	Filing Date	Group Art:
	April 1, 2004	



U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/JV/	AA	6,574,778	06/2003	Chang et al.	716	1
	AB	6,578,174	06/2003	Zizzo	716	1
	AC	6,536,028	03/2003	Katsioulas et al.	716	17
	AD	6,530,074	10/2002	Katsioulas et al.	716	17
	AE	6,366,874	04/2002	Lee et al.	703	14
/JV/	AF	6,334,207	12/2001	Joly et al.	716	17

LC
7/3/09

6,467,074

FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Class	Sub Class	Translation Yes No
AG					

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/	AH	Sutherland, S.; "The IEEE Verilog 1364-2001 Standard What's New, and Why You Need It," 9th Annual International HDL Conference and Exhibition, March 2000. Pp. 1-8.
	AI	Cummings, C.; "Verilog-2001 Behavioral and Synthesis Enhancements," Revised April 2002, pp. 1-23.
	AJ	Cummings, C.; "New Verilog-2001 Techniques for Creating Parameterized Models (or Down with 'define and Death of a defparam!)" HDLCON 2002, pp. 1-10.
	AK	Wu, Y.; and MacDonald, P.; "Testing ASICs with Multiple Identical Cores," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 22, no. 3, March 2003, pp. 327-336.
	AJ	Miodrag Potkonjak et al. "Behavioral Synthesis of Area-Efficient Testable Designs Using Interaction Between Hardware Sharing and Partial Scan," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 14, no. 9, September 1995, pp. 1141-1154.
/JV/	AL	Chih-Chang Lin et al. "Test-Point Insertion: Scan Paths Through Functional Logic," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 17, no. 9, September 1998, pp. 838-851.

EXAMINER: /Jasjit Vidwan/

DATE CONSIDERED: 05/28/2007

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.